

**3.0A, 100V, 1.200 Ohm, P-Channel Power MOSFET**

This P-Channel enhancement mode silicon gate power field effect transistor is an advanced power MOSFET designed, tested and guaranteed to withstand a specified level of energy in the breakdown avalanche mode of operation. All of these power MOSFETs are designed for applications such as switching regulators, switching converters, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17541.

**Ordering Information**

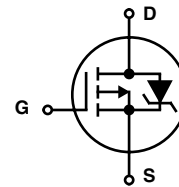
PART NUMBER	PACKAGE	BRAND
IRF9510	TO-220AB	IRF9510

NOTE: When ordering, include the entire part number.

**Features**

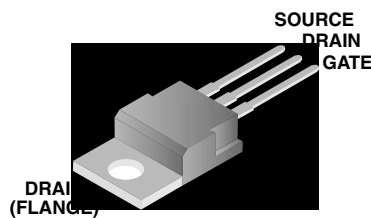
- 3.0A, 100V
- $r_{DS(ON)} = 1.200\Omega$
- Single Pulse Avalanche Energy Rated
- SOA is Power Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance

**Symbol**



**Packaging**

JEDEC TO-220AB



# IRF9510

## Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

	IRF9510	UNITS	
Drain to Source Voltage (Note 1) . . . . .	$V_{DS}$	-100	V
Drain to Gate Voltage ( $R_{GS} = 20\text{k}\Omega$ ) (Note 1) . . . . .	$V_{DGR}$	-100	V
Continuous Drain Current . . . . .	$I_D$	-3.0	A
$T_C = 100^\circ\text{C}$ . . . . .	$I_D$	-2.0	A
Pulsed Drain Current (Note 3) . . . . .	$I_{DM}$	-12	A
Gate to Source Voltage . . . . .	$V_{GS}$	$\pm 20$	V
Maximum Power Dissipation . . . . .	$P_D$	20	W
Linear Derating Factor . . . . .		0.16	W/ $^\circ\text{C}$
Single Pulse Avalanche Energy Rating (Note 4) . . . . .	$E_{AS}$	190	mJ
Operating and Storage Temperature Range . . . . .	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$
Maximum Temperature for Soldering			
Leads at 0.063in (1.6mm) from Case for 10s . . . . .	$T_L$	300	$^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	$T_{pkg}$	260	$^\circ\text{C}$

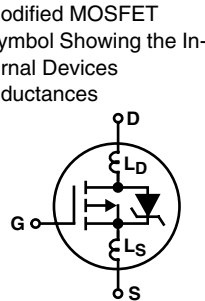
**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

**NOTE:**

- $T_J = 25^\circ\text{C}$  to  $125^\circ\text{C}$ .

## Electrical Specifications $T_C = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$ , (Figure 10)	-100	-	-	V
Gate to Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = -250\mu\text{A}$	-2.0	-	-4.0	V
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20\text{V}$	-	-	$\pm 100$	nA
Zero-Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}$	-	-	-25	$\mu\text{A}$
		$V_{DS} = 0.8 \times \text{Rated } BV_{DSS}, V_{GS} = 0\text{V}, T_C = 125^\circ\text{C}$	-	-	-250	$\mu\text{A}$
On-State Drain Current (Note 2)	$I_{D(ON)}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, V_{GS} = -10\text{V}$ , (Figure 7)	-3.0	-	-	A
Drain to Source On Resistance (Note 2)	$r_{DS(ON)}$	$V_{GS} = -10\text{V}, I_D = -1.5\text{A}$ , (Figures 8, 9)	-	1.000	1.200	$\Omega$
Forward Transconductance (Note 2)	$g_{fs}$	$V_{DS} > I_{D(ON)} \times r_{DS(ON)MAX}, I_D = -1.5\text{A}$ , (Figure 12)	0.8	1.1	-	S
Turn-On Delay Time	$t_{d(ON)}$	$V_{DD} = 0.5 \times \text{Rated } BV_{DSS}, I_D \approx -3.0\text{A}$ , $R_G = 50\Omega, V_{GS} = 10\text{V}$ , (Figures 17, 18)	-	15	30	ns
Rise Time	$t_r$	$R_L = 15.7\Omega$ for $V_{DSS} = 50\text{V}$	-	30	60	ns
Turn-Off Delay Time	$t_{d(OFF)}$	$R_L = 12.3\Omega$ for $V_{DSS} = 40\text{V}$	-	20	40	ns
Fall Time	$t_f$	MOSFET Switching Times are Essentially Independent of Operating Temperature	-	20	40	ns
Total Gate Charge (Gate to Source + Gate to Drain)	$Q_g(\text{TOT})$	$V_{GS} = -10\text{V}, I_D = -3\text{A}, V_{DS} = 0.8 \times \text{Rated } BV_{DSS}$ , (Figures 14, 19, 20) Gate Charge is Essentially Independent of Operating Temperature	-	8.5	11	nC
Gate to Source Charge	$Q_{gs}$		-	3.8	-	nC
Gate to Drain "Miller" Charge	$Q_{gd}$		-	4.7	-	nC
Input Capacitance	$C_{ISS}$	$V_{GS} = 0\text{V}, V_{DS} = -25\text{V}, f = 1.0\text{MHz}$ , (Figure 11)	-	180	-	pF
Output Capacitance	$C_{OSS}$		-	85	-	pF
Reverse Transfer Capacitance	$C_{RSS}$		-	30	-	pF
Internal Drain Inductance	$L_D$	Measured From the Contact Screw on Tab to Center of Die	-	3.5	-	nH
		Measured From the Drain Lead, 6mm (0.25in) From Package to Center of Die	-	4.5	-	nH
Internal Source Inductance	$L_S$	Measured From The Source Lead, 6mm (0.25in) From Header to Source Bonding Pad	-	7.5	-	nH
Junction to Case	$R_{\theta JC}$		-	-	6.4	$^\circ\text{C/W}$
Junction to Ambient	$R_{\theta JA}$	Typical Socket Mount	-	-	62.5	$^\circ\text{C/W}$



Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Continuous Source to Drain Current	$I_{SD}$	Modified MOSFET Symbol Showing the Integral Reverse P-N Junction Diode	-	-	-3.0	A
Pulse Source to Drain Current (Note 3)	$I_{SDM}$		-	-	-12	A
Source to Drain Diode Voltage(Note 2)	$V_{SD}$	$T_C = 25^{\circ}C, I_{SD} = -3.0A, V_{GS} = 0V,$ (Figure 13)	-	-	-1.5	V
Reverse Recovery Time	$t_{rr}$	$T_J = 150^{\circ}C, I_{SD} = -3.0A, dI_{SD}/dt = 100A/\mu s$	-	120	-	ns
Reverse Recovered Charge	$Q_{RR}$	$T_J = 150^{\circ}C, I_{SD} = -3.0A, dI_{SD}/dt = 100A/\mu s$	-	6.0	-	$\mu C$

NOTES:

2. Pulse test: pulse width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
3. Repetitive rating: pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
4.  $V_{DD} = 25V$ , starting  $T_J = 25^{\circ}C$ ,  $L = 31.7mH$ ,  $R_G = 25\Omega$ , peak  $I_{AS} = 3.0A$ . See Figures 15, 16.

Typical Performance Curves Unless Otherwise Specified

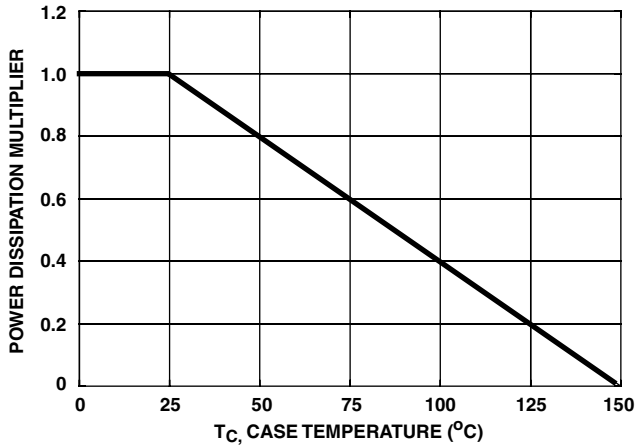


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

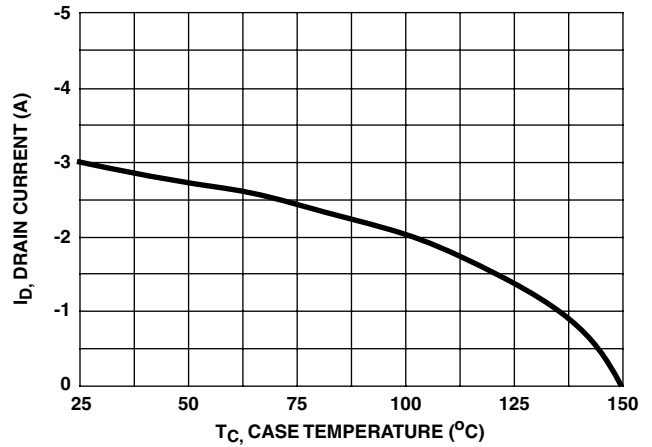


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

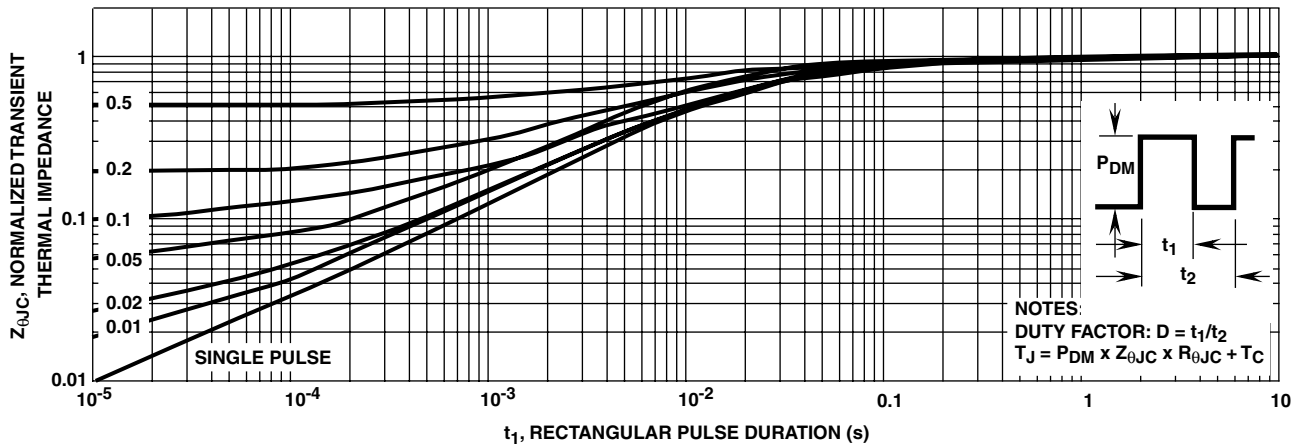


FIGURE 3. NORMALIZED TRANSIENT THERMAL IMPEDANCE

Typical Performance Curves Unless Otherwise Specified (Continued)

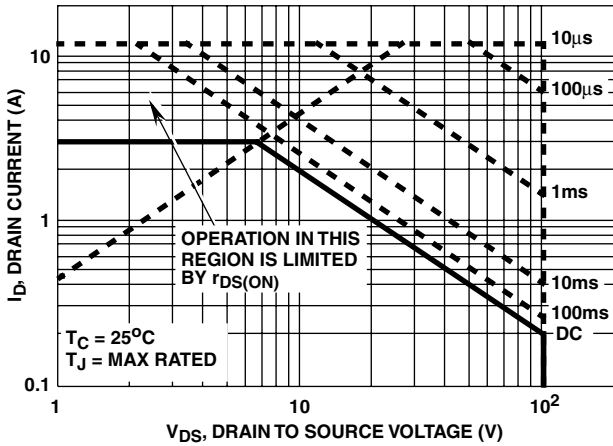


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

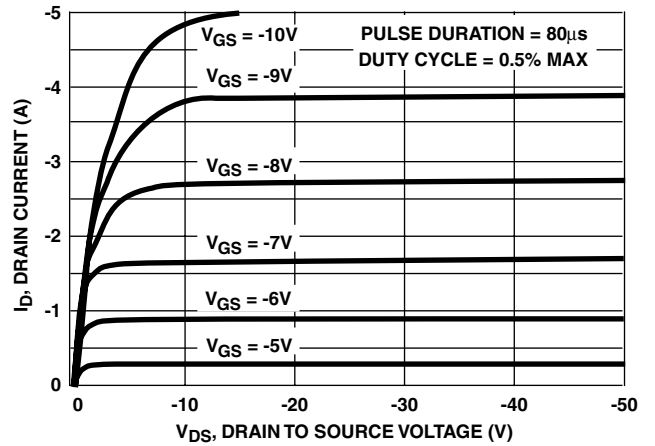


FIGURE 5. OUTPUT CHARACTERISTICS

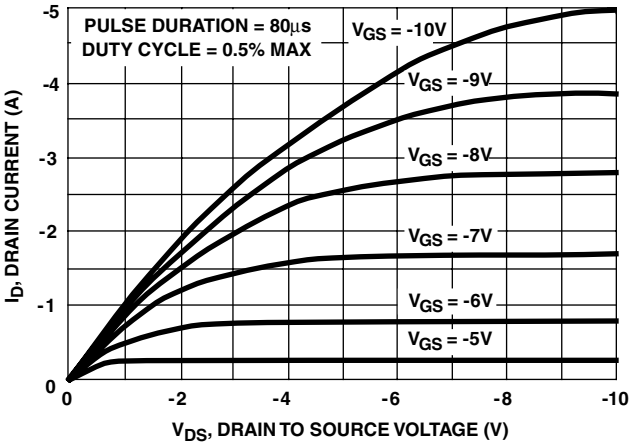


FIGURE 6. SATURATION CHARACTERISTICS

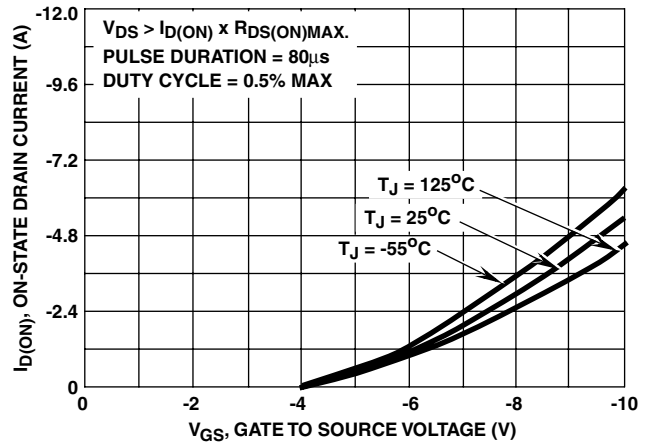


FIGURE 7. TRANSFER CHARACTERISTICS

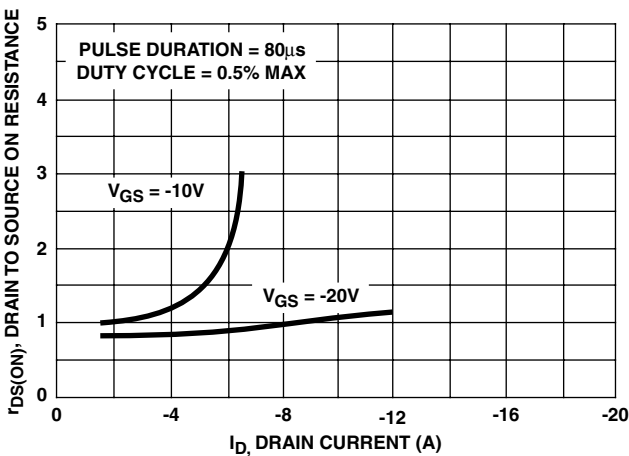


FIGURE 8. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

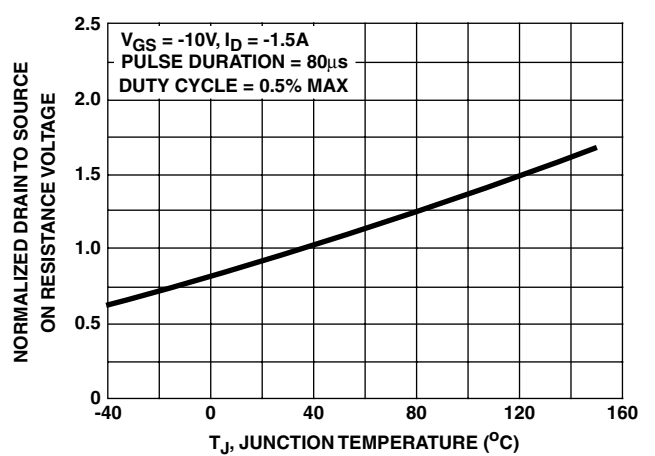


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

Typical Performance Curves Unless Otherwise Specified (Continued)

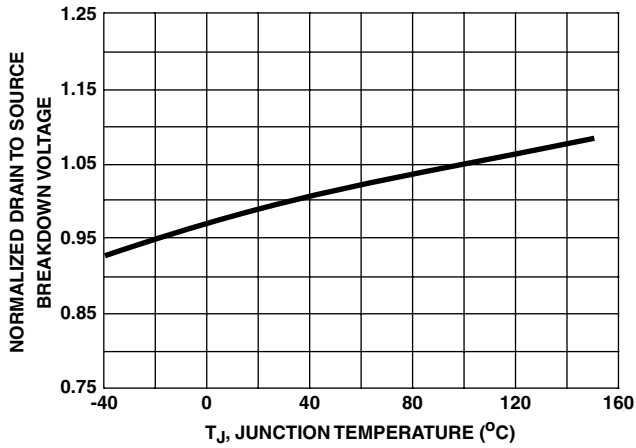


FIGURE 10. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

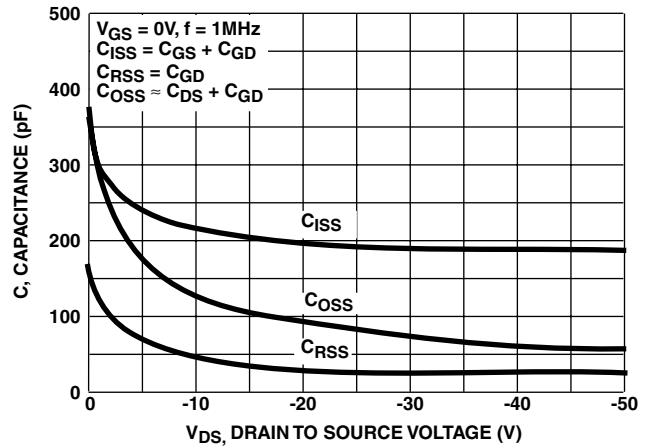


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

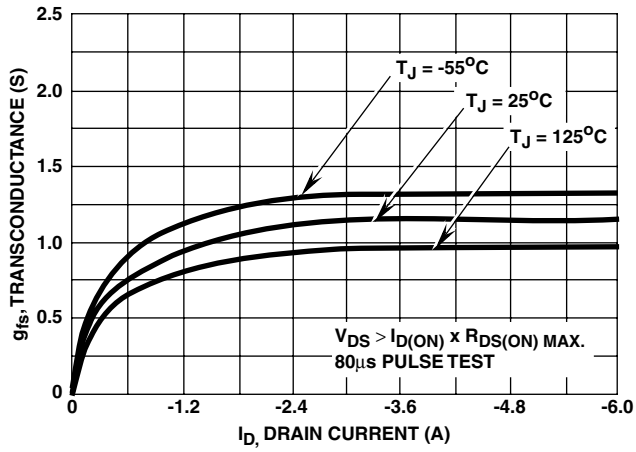


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

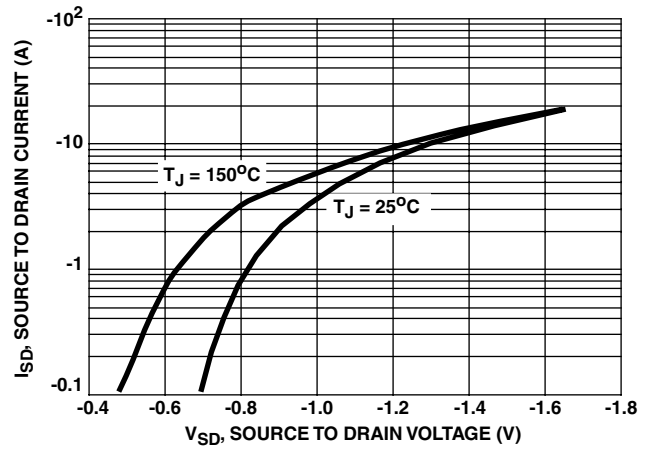


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

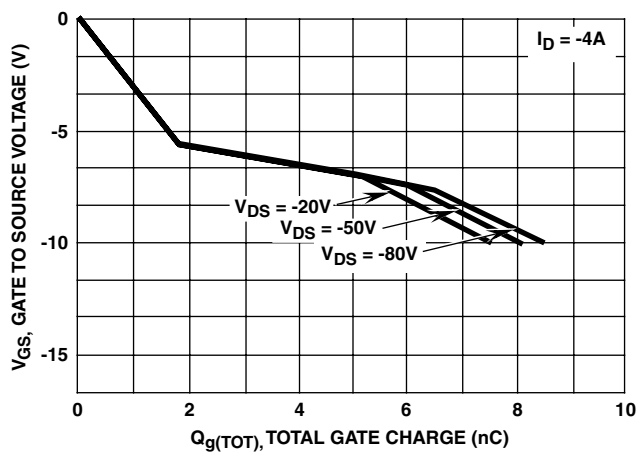


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

Test Circuits and Waveforms

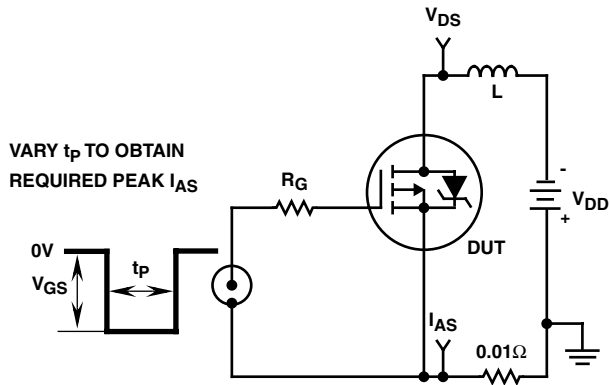


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

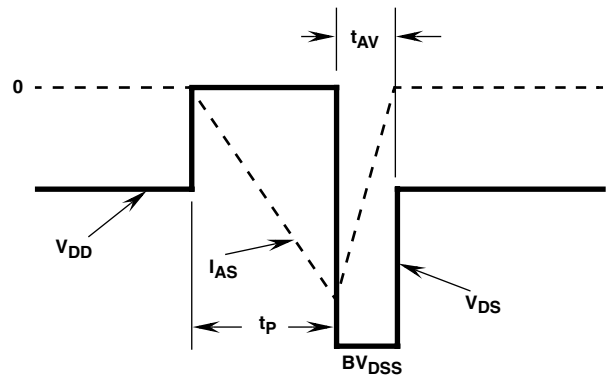


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

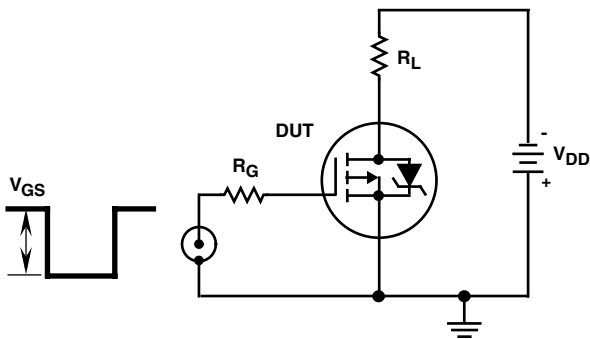


FIGURE 17. SWITCHING TIME TEST CIRCUIT

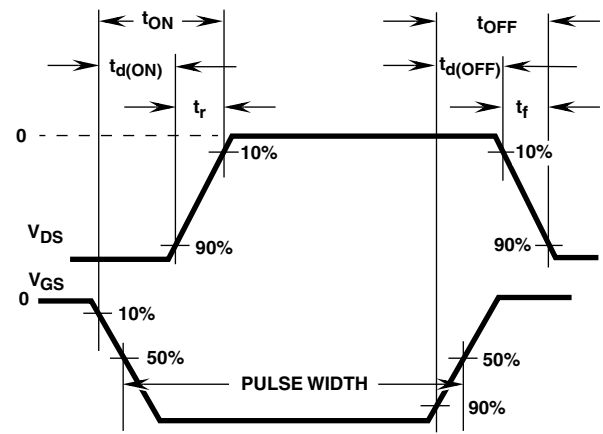


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

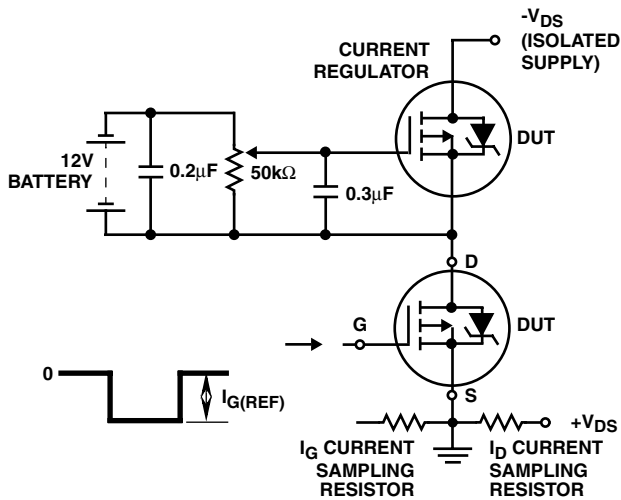


FIGURE 19. GATE CHARGE TEST CIRCUIT

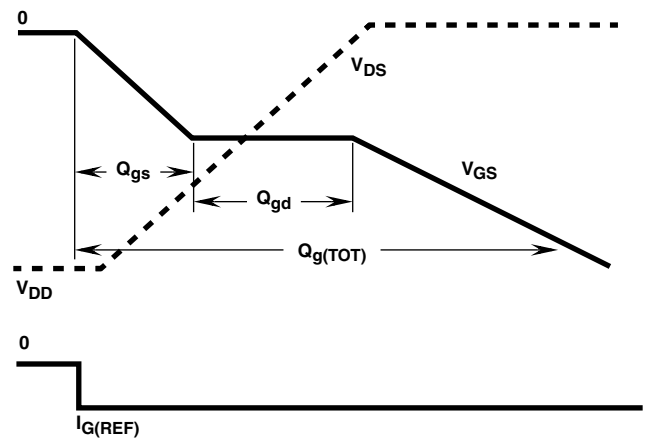


FIGURE 20. GATE CHARGE WAVEFORMS

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DOMET <sup>TM</sup>	HiSeC <sup>TM</sup>	PowerTrench <sup>®</sup>	SuperSOT <sup>TM</sup> -8	
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FACT <sup>TM</sup>	MicroPak <sup>TM</sup>	Quiet Series <sup>TM</sup>	UHC <sup>TM</sup>	
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Datasheet Identification	Product Status	Definition
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